

Search Notes

Application No.

10/029,273

Examiner

David E. Bochna

Applicant(s)

CHIU ET AL.

Art Unit

3679

SEARCHED

Class	Subclass	Date	Examiner
285	134.1		
	135.1		
	419		
	913		
	286.1		
	288.6		
74	424.81		
	424.82		
	424.83		
	424.85		
	424.86		
	424.87		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR